

Notice of References Cited	Application/Control No. 10/801,072	Applicant(s)/Patent Under Reexamination KUCHEROV ET AL.	
	Examiner Alan Diamond	Art Unit 1753	Page 1 of 1

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	V	Hagelstein et al, "Thermally-Induced Current Injection across an npn Junction," 22nd International Conference on Thermoelectrics, pages 554-557, August 17-21, 2003.
	W	Hagelstein et al, "Study of Emitter Structures for InSb Thermal Diodes," 22nd International Conference on Thermoelectrics, pages 578-581, August 17-21, 2003.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Alan Diamond

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